

RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 14:43

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

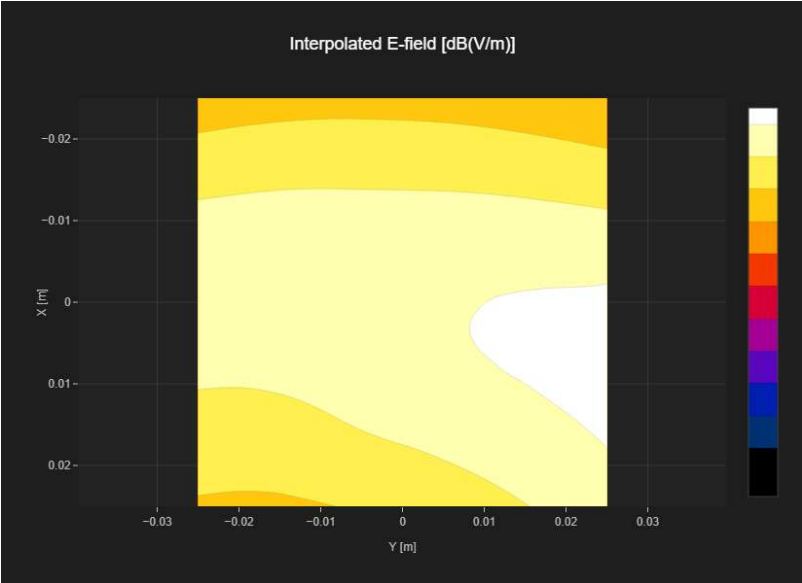
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	128	824.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
31.79	29.62	3.63	33.25



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 14:46

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

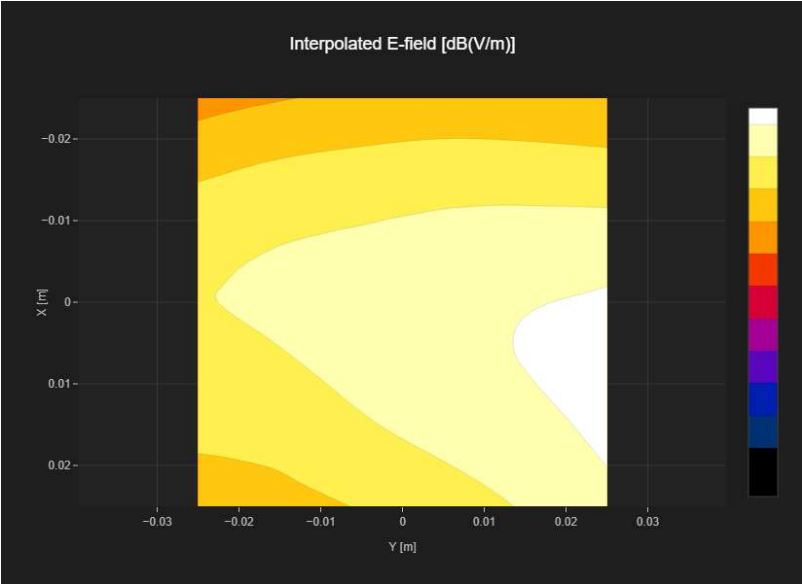
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	190	836.6

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
33.3	30.75	3.63	34.38



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 14:52

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

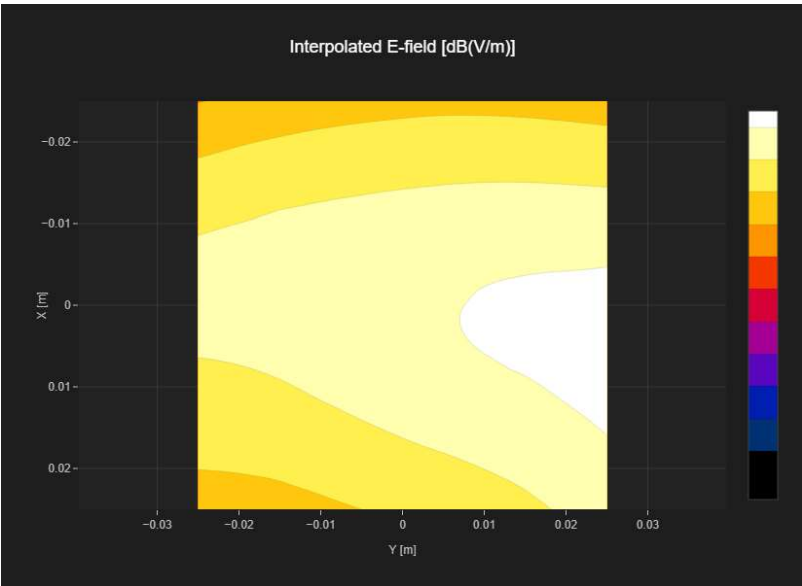
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	251	848.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
32.09	29.85	3.63	33.48



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 15:02

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

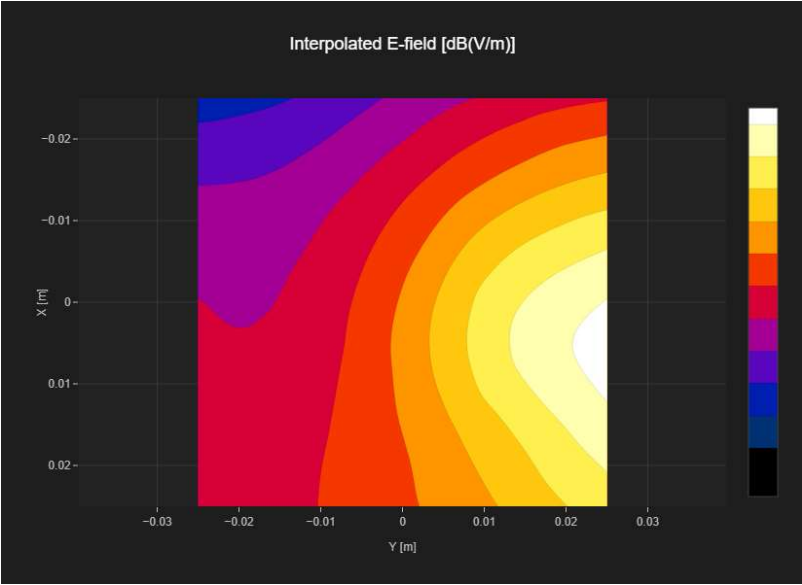
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	128	824.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
37.04	29.74	3.63	33.37



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 15:11

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

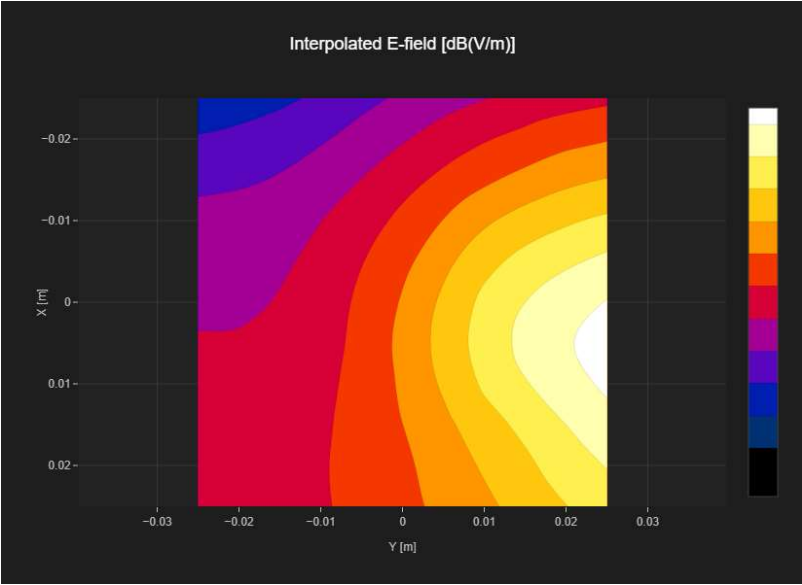
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	190	836.6

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
36.91	29.52	3.63	33.15



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 15:14

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

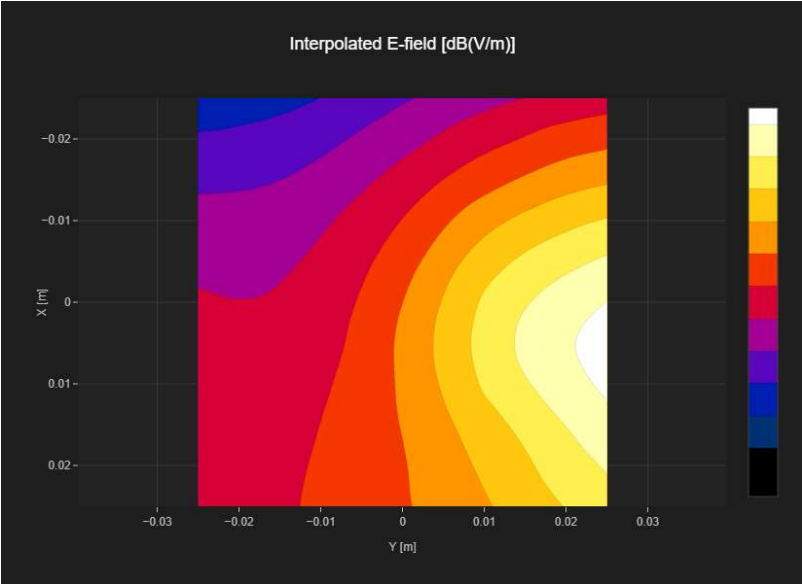
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	251	848.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
36.2	28.76	3.63	32.39



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 14:16

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

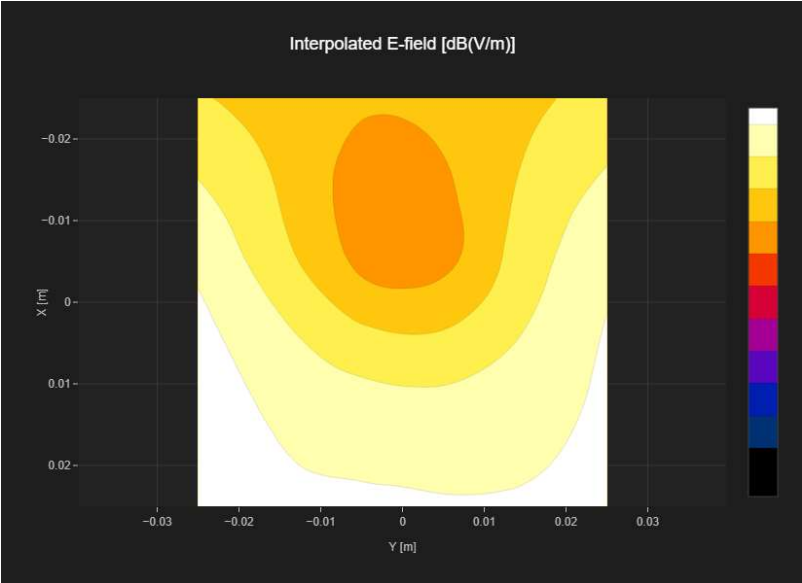
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	512	1850.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.43	20.64	3.63	24.27



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 14:21

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

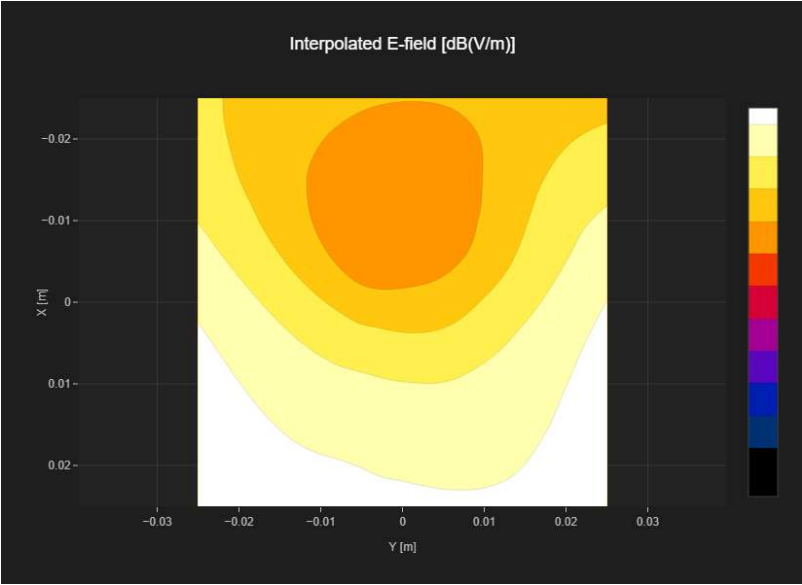
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	661	1880.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.56	20.62	3.63	24.25



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 14:32

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

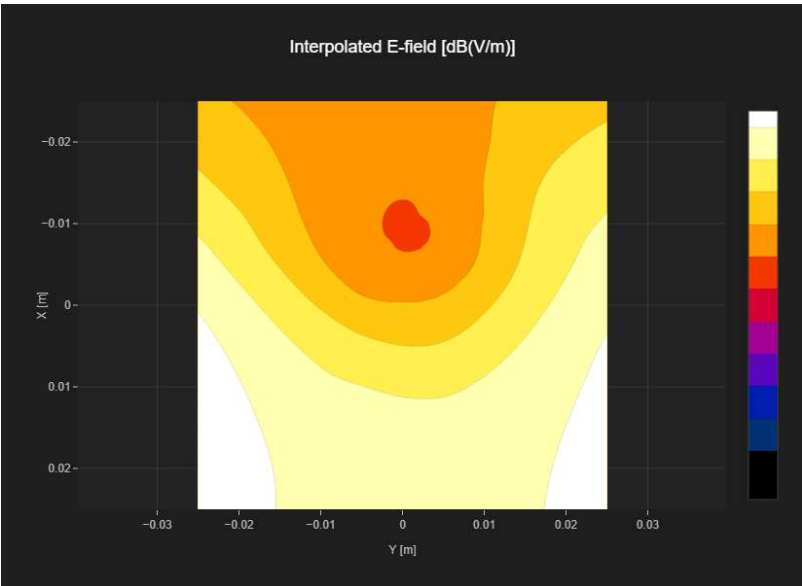
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	810	1909.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.69	20.48	3.63	24.11



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 13:25

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

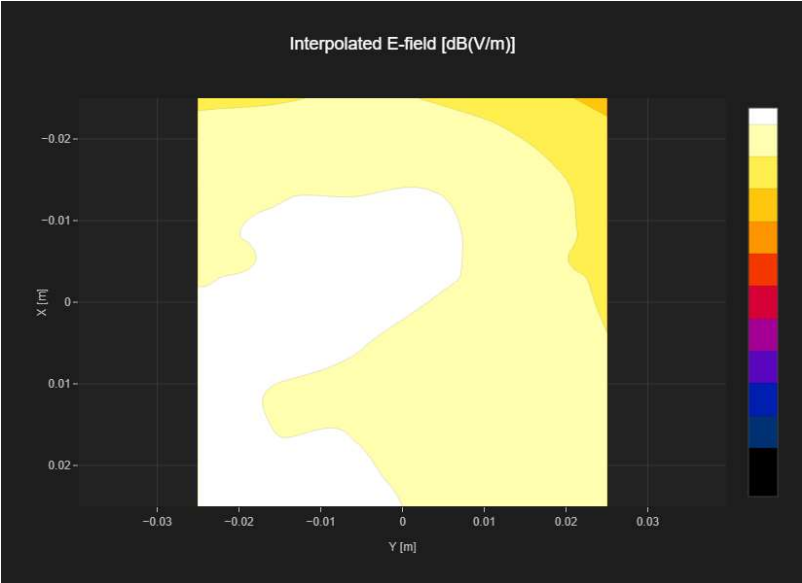
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	509202	2546.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

E _{max} [dB(V/m)]	E _{avg50x50 max} [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
14.61	13.69	-1.64	12.05



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 13:35

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

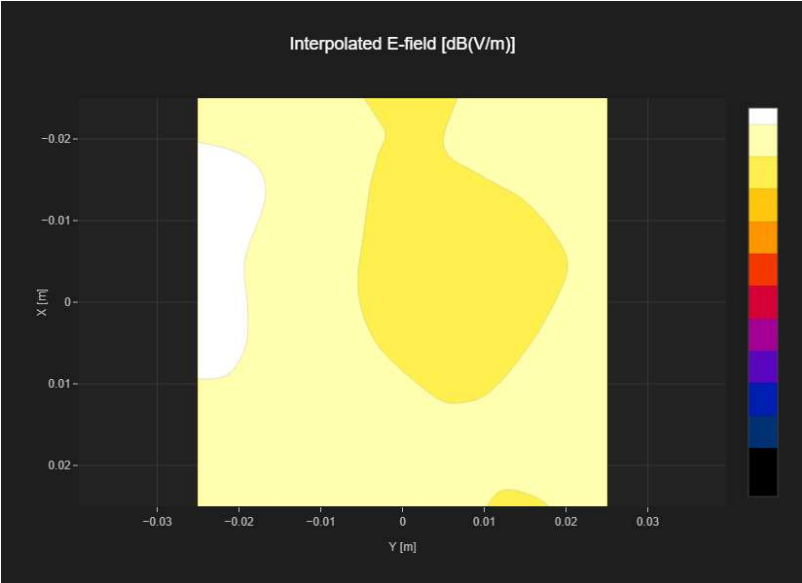
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	518598	2592.99

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

E _{max} [dB(V/m)]	E _{avg50x50 max} [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
14.27	13.44	-1.64	11.8



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 13:58

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

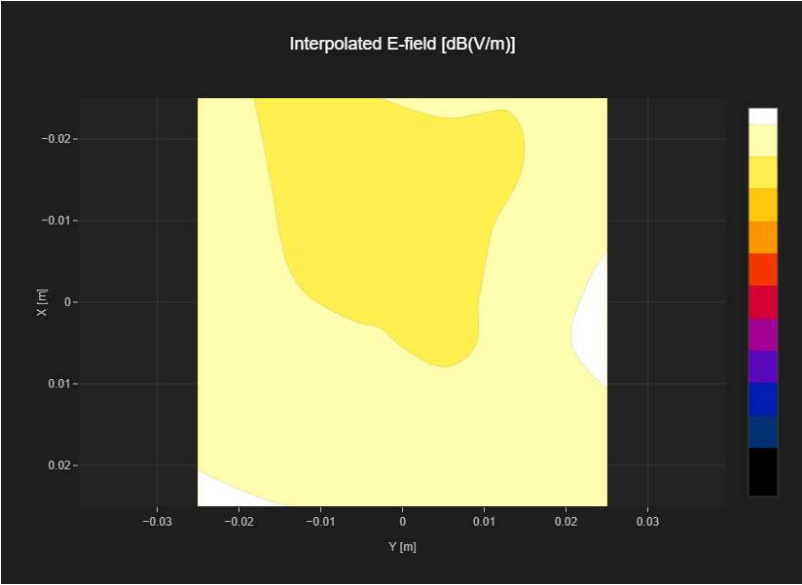
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	528000	2640.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
13.44	13.24	-1.64	11.6



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 11:44

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

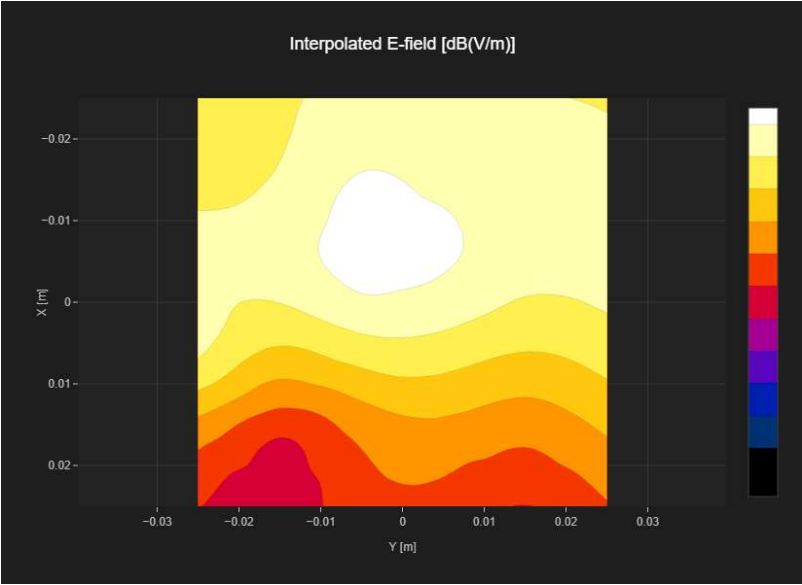
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	633334	3500.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
28.77	25.48	-1.64	23.84



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 11:22

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

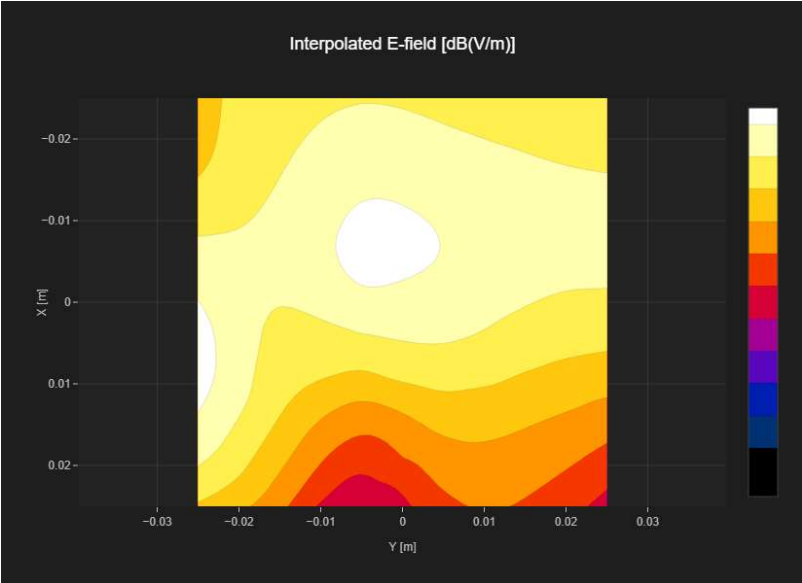
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	650000	3750.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

E _{max} [dB(V/m)]	E _{avg50x50 max} [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
29.9	27.08	-1.64	25.44



RF Interference Potential Test Report

Measurement performed on May 08, 2025 at 11:37

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A566U1

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1447	March 19, 2025

Communication Systems

Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	662000	3930.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
30.32	27.74	-1.64	26.1

